Se	arcn	NOTE	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/673,367	TANAKA ET AL.	
Examiner	Art Unit	
Thanh-Truc Trinh	1753	

SEARCHED			
Class	Subclass	Date	Examiner
136	256	12/26/2006	π
420	561	12/26/2006	π
420	562	12/26/2006	п
257	746	12/26/2006	π
257	746-779	12/26/2006	π
Update		6/26/2007	π
420	560-562	6/26/2007	π

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST Search	12/12/2006	. п
Consulting Anthony Fick	12/21/2006	π
Inventor Search	12/26/2006	π
Update EASt and Inventor Search	6/26/2007	π
Consulting with SPE	6/26/2007	π
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